Supplementary Material

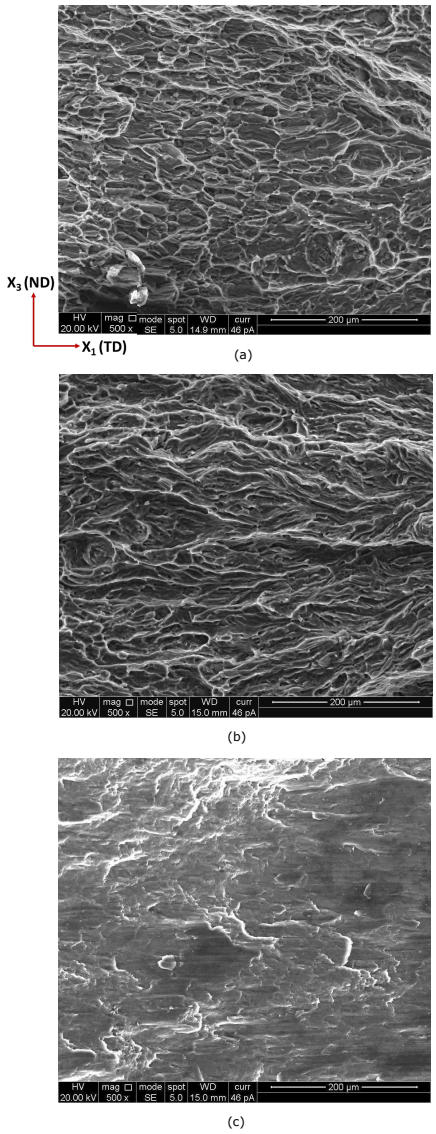
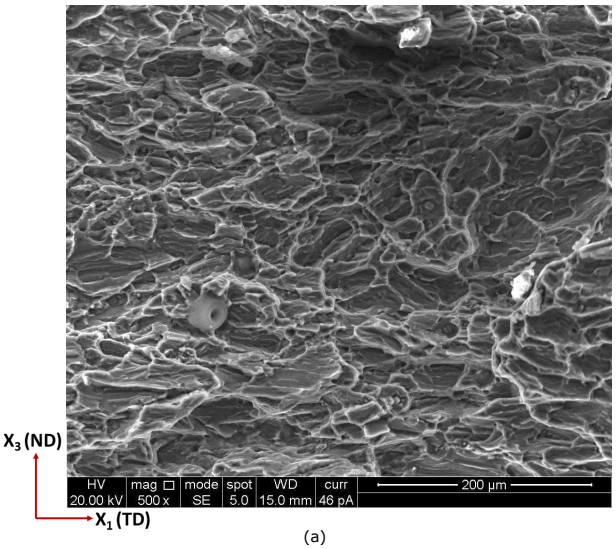
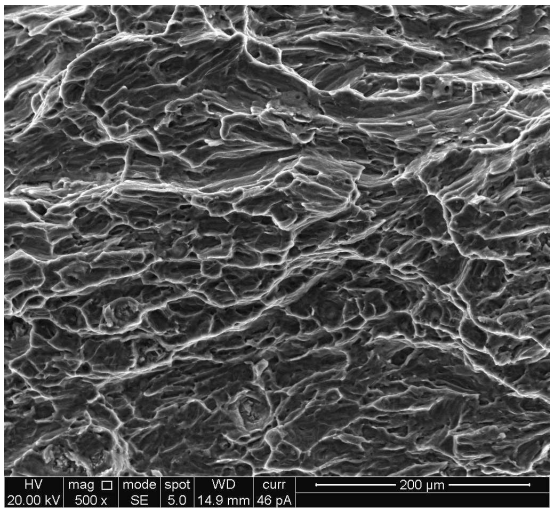


Figure S1: Low magnification SEM fractographs at the crack initiation region corresponding to: (a) S4PBS (b) AS4PB-2S and (c) AS4PB-0S.



(a)



(b)

Figure S2: Low magnification SEM fractographs at the specimen mid-thickness taken at a distance of about 500 μm away from the crack initiation region corresponding to: (a) S4PBS and (b) AS4PB-2S.

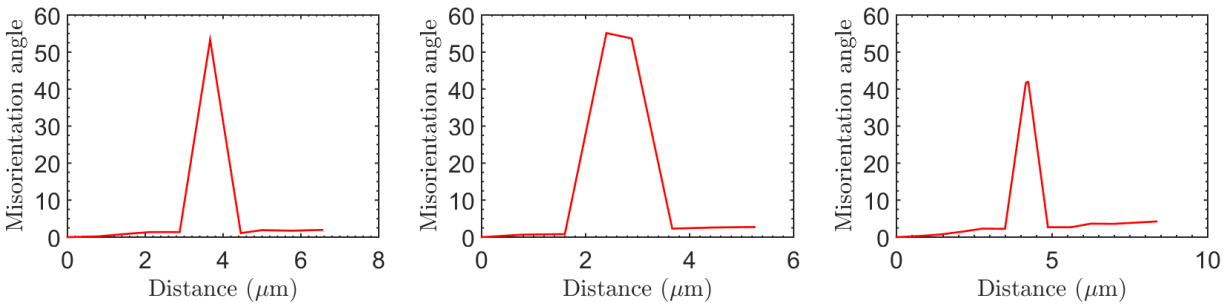
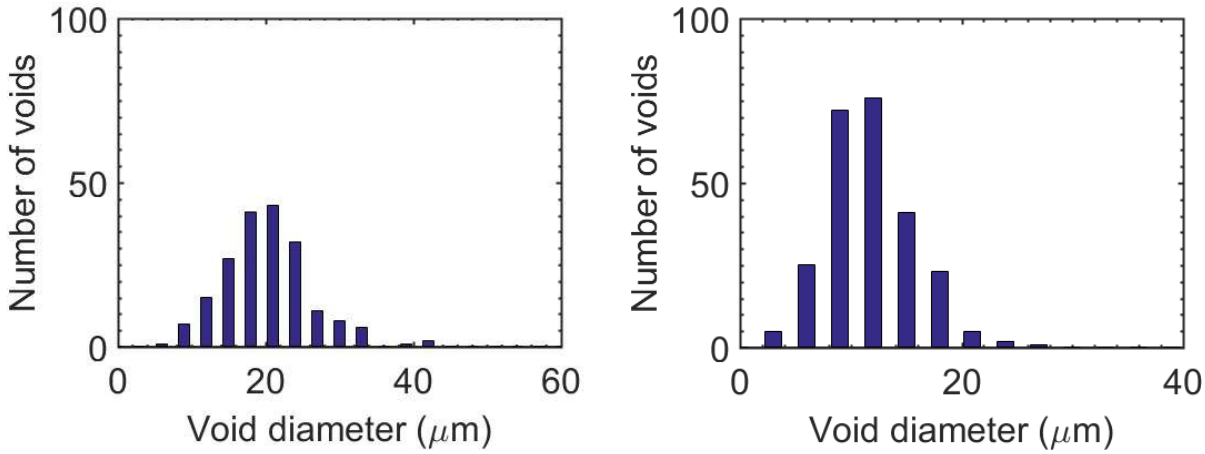
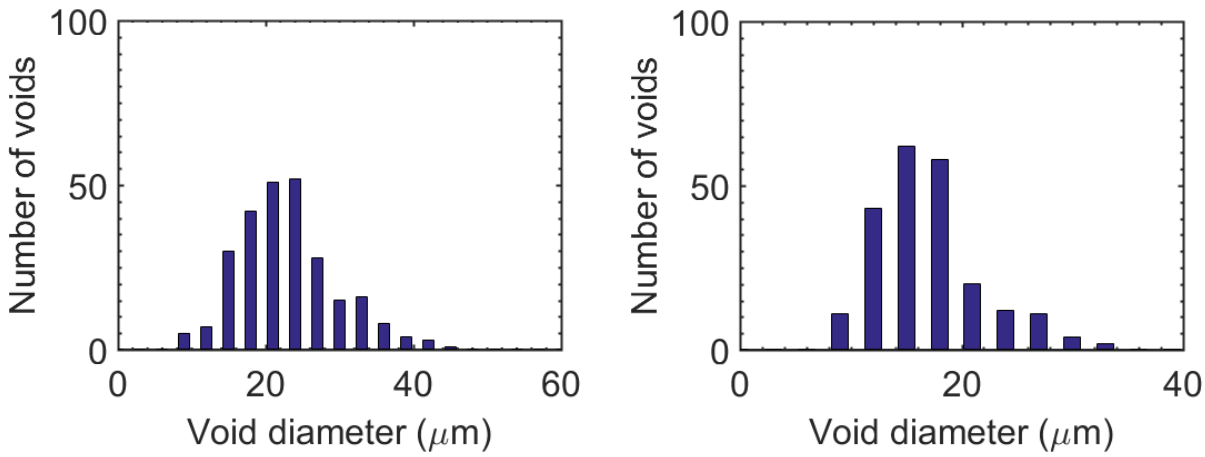


Figure S3: Plots of misorientation angle taken along lines marked as (a) 1, (b) 2 and (c) 3 in Fig. 13(c).



(a) (b)

Figure S4: Void size distribution near the notch root obtained from several fractographs (see for example, Fig. S1) for: (a) S4PBS and (b) AS4PB-2S.



(a) (b)

Figure S5: Void size distribution near the extended crack (at a distance of about 500 μm away from notch tip) obtained from several fractographs (see for example, Fig. S2) for: (a) S4PBS and (b) AS4PB-2S.